1. (Currently Amended) A method for treating a metallic implantan implant surface

intended for implantation into bone tissue, said method comprising:

treating the metallic implant surface with an aqueous solution of hydrofluoric acid,

resulting in an etching process, wherein the concentration of the hydrofluoric acid is less than 0.5

M, and wherein the metallic implant surface is treated for an etching period of up to 180 seconds

at room temperature, said etching period being measured from the formation of the first bubble

of H<sub>2</sub> (g) at the implant surface, thereby

providing an oxide layer with fluorine and/or fluoride incorporated therein and

distributed throughout the oxide layer on at least a part of the implant surface, and

providing a microroughness comprising pores having a pore diameter within a range of 1

nm to 1  $\mu$ m of  $\leq$  1  $\mu$ m and a pore depth within a range of 1 nm to 500 nm of  $\leq$  500 nm, wherein

the implant surface is a metallic implant surface, by treating the metallic implant surface with an

aqueous solution of hydrofluoric acid, resulting in an etching process, wherein the concentration

of the hydrofluoric acid is less than 0.5 M, and wherein the metallic implant surface is treated for

an etching period of up to 180 seconds at room temperature, said etching period being measured

from the formation of the first bubble of  $H_2$  (g) at the implant surface.

2-27. (Cancelled).

28. (Previously Presented) The method according to claim 1, wherein the pore diameter

is within the range of 50 nm to 1 µm and the pore depth is within the range of 50 to 500 nm.

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29. (Previously Presented) The method according to claim 1, wherein a root-mean-

square roughness ( $R_q$  and/or  $S_q$ ) of  $\leq 250$  nm is provided.

30. (Previously Presented) The method according to claim 1, wherein an average atomic

concentration of at least 0.2 at% fluorine and/or fluoride is provided.

31. (Previously Presented) The method according to claim 30, wherein the average

atomic concentration of fluorine and/or fluoride is within the range of 0.4-7 at%.

32. (Cancelled)

33. (Previously Presented) The method according to claim 1, wherein the concentration

of the hydrofluoric acid is 0.1 M and the etching period is up to 60 sec at room temperature.

34. (Previously Presented) The method according to claim 1, further comprising

providing a macroroughness on the implant surface prior to providing the fluorine and/or

fluoride and prior to providing the microroughness.

35. (Previously Presented) The method according to claim 34, wherein the

macroroughness is provided by blasting the implant surface.

36. (Previously Presented) The method according to claim 1, wherein said metallic

implant surface is made of commercially pure titanium or an alloy of titanium.

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37. (Previously Presented) An implant for implantation into bone tissue having an

implant surface at least part of which has been treated with a method according to claim 1.

38. (Currently Amended) An implant for implantation into bone tissue having an implant

surface, wherein

the implant surface is a metallic implant surface,

there is an oxide layer on at least part of the implant surface,

said oxide layer having fluorine and/or fluoride incorporated therein, and

at least a part of the implant surface comprises a microroughness which comprise pores

having a diameter of  $< 1 \mu m$  within a range of 1 nm to 1  $\mu m$  and a pore depth-of < 500 nm within

a range of 1 nm to 500 nm, wherein the microroughness comprises peaks having a peak width, at

half the pore depth, of from 15 to 150% of the pore diameter.

39. (Previously Presented) The implant according to claim 38, wherein the pore diameter

is within the range of 50 nm to 1  $\mu$ m and the pore depth is within the range of 50 to 500 nm.

40. (Previously Presented) The implant according to claim 38, wherein the

microroughness has a root-mean-square roughness ( $R_q$  and/or  $S_q$ ) of  $\leq 250$  nm.

41. (Previously Presented) The implant according to claim 38, wherein at least a part of

the implant surface has an average atomic concentration of at least 0.2 at% fluorine and/or

fluoride.

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42. (Previously Presented) The implant according to claim 41, wherein the average atomic concentration of fluorine and/or fluoride is within the range of 0.4-7 at%.

43. (Previously Presented) The implant according to claim 38, wherein the implant surface further comprises a macroroughness.

44. (Previously Presented) The implant according to claim 38, wherein said implant is a metallic implant.

45. (Previously Presented) The implant according to claim 44, wherein said metallic implant surface is made of commercially pure titanium or an alloy of titanium.

46. (Previously Presented) The implant according to claim 38, wherein the implant is a dental implant.

47. (Previously Presented) The implant according to claim 38, wherein the implant is an orthopaedic implant.